## Notice of References Cited Application/Control No. 10/783,180 Examiner SANG KIM Applicant(s)/Patent Under Reexamination WIER, FRANZ Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,149,095	11-2000	Specht et al.	242/374
	В	US-6,241,173 b1	06-2001	Wier, Franz	242/382
	· C	US-5,397,075	03-1995	Behr, Leonard W.	242/374
	D	US-6,698,677 b1	03-2004	Happ et al.	242/374
	Ε	US-6,450,435 b2	09-2002	Junker et al.	242/374
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	x	

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